

SPECIFICATION

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SPEC. NO.: PS-55928-XXXXX-XXX REVISION: E

PRODUCT NAME: USB 3.1 A TYPE

PRODUCT NO: 5592X \ 5593X \ 5597X \ 5598X \ 3012X \ 3013X

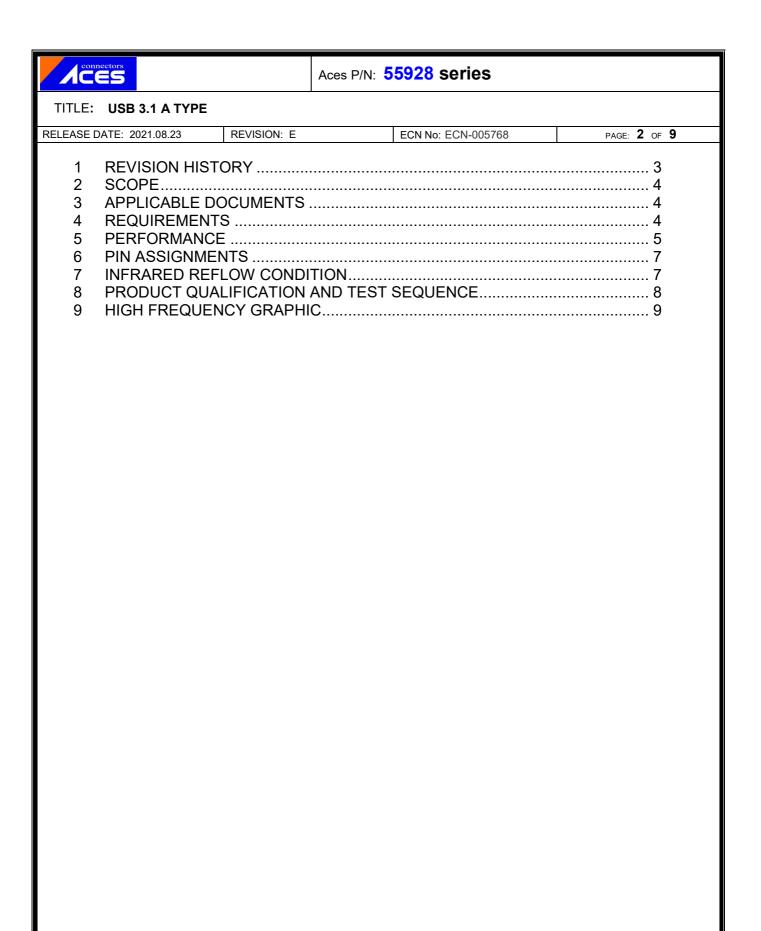
3015X \ 3014X \ 301XX \ 53935 \ 311XX SERIES

PREPARED: CHECKED: APPROVED:

LIAO WAN TING | TENG CHANG HO | KUO JUNG HSUN

DATE: DATE:

2021.08.23 2021.08.23 2021.08.23



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| connectors |
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1 Revision History

| Rev. | ECN# | Revision Description | Prepared | Date |
|------|-------------|------------------------------|---------------|------------|
| 0 | ECN-1504472 | NEW SPEC | ERIC | 2015.04.29 |
| Α | ECN-1705458 | MODIFY Current SALT SPRAY & | TINA | 2017.05.25 |
| | | Insertion / Extraction Force | | |
| В | ECN-1707093 | ADD 3014X SERIES | TINA | 2017.07.07 |
| С | ECN-1709033 | ADD 301XX SERIES | TINA | 2017.09.04 |
| D | ECN-2004170 | ADD 53935 & 311XX SERIES | LIAO WAN TING | 2020.04.29 |
| Е | ECN-005768 | Change title: USB 3.1 A TYPE | LIAO WAN TING | 2021.08.23 |
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2 SCOPE

This specification covers performance, tests and quality requirements for USB 3.0 connector.

3 APPLICABLE DOCUMENTS

EIA-364: **ELECTRONICS INDUSTRIES ASSOCIATION**

4 REQUIREMENTS

- 4.1 Design and Construction
 - 4.1.1 Product shall be of design, construction and physical dimensions specified on applicable product drawing.
 - 4.1.2 All materials conform to R.o.H.S. and the standard depends on TQ-WI-140101.
- 4.2 Materials and Finish
 - 4.2.1 Contact: High performance copper alloy

Finish: (a) Contact Area: Refer to the drawing.

- (b) Under plate: Refer to the drawing.
- (c) Solder area: Refer to the drawing.
- 4.2.2 Housing: Thermoplastic or Thermoplastic High Temp.
- 4.2.3 Shell: Refer to the drawing.
- 4.3 Ratings
 - 4.3.1 Voltage: 30 Volts AC (per pin)
 - 4.3.2 Current: 1.8 A FOR PIN 1 AND PIN 4
 - 0.25A FOR ALL THE OTHER CONTACTS
 - 4.3.3 Operating Temperature : -55°C to +85°C



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5 Performance

5.1. Test Requirements and Procedures Summary

| Item | Requirement | Standard | | | |
|---------------------------------|--|---|--|--|--|
| Examination of Product | Product shall meet requirements of applicable product drawing and specification. | Visual, dimensional and functional per applicable quality inspection plan. | | | |
| | ELECTRICAL | | | | |
| Item | Requirement | Standard | | | |
| Low Level Contact Resistance | 30 mΩ (Max) initial for VBUS and GND contacts. 50 mΩ (Max) initial for all other contacts. 40 mΩ (Max) after for VBUS and GND contacts. 60 mΩ (Max) after for all other contacts. | Mate connectors, measure by dry circuit, 20mV Max., 100mA Max. (EIA-364-23) | | | |
| Insulation Resistance | 100 M Ω Min. | Unmated and mated connectors, apply 500 V DC between adjacent terminals. (EIA-364-21) | | | |
| Dielectric withstanding voltage | No discharge, flashover or breakdown. Current leakage: 1 mA max. | 100 VAC Min. at sea level for 1 minute. Test between adjacent contacts of unmated and mated connectors. (EIA-364-20) | | | |
| Temperature rise | 30°ℂ Max. Change allowed | A current of 1.8 A shall be applied to VBUS pin and its corresponding GND pin. Additionally, a minimum current of 0.25 A shall be applied to all tile other contacts. when measured at an ambient temperature of 25 °C. (EIA-364-70 METHOD 2) | | | |
| Differential Impedance | 90Ω +/-15Ω Reefer to High Frequency Graphic Figure 1 | Mated connector 50 ps (20%-80%) Risetime. | | | |
| | MECHANICAL | | | | |
| Item | Requirement | Standard | | | |
| Durability | 5000 cycles. | The durability test shall be done at a maximum rate of 200 cycles per hour and no physical damage to any part of the connector and cable assembly shall occur. (EIA-364-09) | | | |



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| | | Operation Speed: | | | | |
|--------------------------------------|--|--|--|--|--|--|
| | Insertion Force: 25 N Max. | Operation Speed : | | | | |
| | Extraction Force: | 12.5 ± 3 mm/minute | | | | |
| Insertion / Extraction Force | 10 N~25N (initial) | Measure the force required to | | | | |
| | 8 N~25N (after test) | mate/unmate connector. | | | | |
| | on zon (alter test) | (EIA-364-13) | | | | |
| | | The electrical load condition shall | | | | |
| | | be 100 mA maximum for all | | | | |
| | | contacts. Subject to a simple | | | | |
| | | harmonic motion having amplitude of 0.76mm (1.52mm maximum total excursion) in frequency between the limits of 10 and 55 Hz. The entire frequency range, from 10 to 55 Hz and return to 10 Hz, shall be traversed in approximately | | | | |
| | | | | | | |
| | | | | | | |
| ver e | | | | | | |
| Vibration | 1 μs Max. | | | | | |
| | | | | | | |
| | | | | | | |
| | | 1 minute. This motion shall be | | | | |
| | | applied for 2 hours in each of three | | | | |
| | | mutually perpendicular directions. | | | | |
| | | (EIA-364-28 Condition I) | | | | |
| | ENVIRONMENTAL | | | | | |
| Item | Requirement | Standard | | | | |
| Resistance to Reflow | See Product Qualification and Test | | | | | |
| Soldering Heat | Sequence Group 8 | 60~120sec. | | | | |
| Coldering Fiedt | | Heat : 230°C Min., 40sec Min. | | | | |
| | | Peak Temp. : 260°C Max, | | | | |
| | | • | | | | |
| | | 10sec Max. | | | | |
| | | (EIA-364-56) | | | | |
| | | Mate module and subject to follow | | | | |
| | | condition for b cycles | | | | |
| | 0 0 1 10 15 15 17 | condition for 5 cycles. | | | | |
| Thermal Shock | See Product Qualification and Test | 1 cycles: | | | | |
| Thermal Shock | See Product Qualification and Test Sequence Group 4 | 1 cycles: -55 +0/-3 °C, 30 minutes | | | | |
| Thermal Shock | | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes | | | | |
| Thermal Shock | | 1 cycles: -55 +0/-3 °C, 30 minutes | | | | |
| Thermal Shock | | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes | | | | |
| Thermal Shock | | 1 cycles: -55 +0/-3 ℃, 30 minutes +85 +3/-0 ℃, 30 minutes (EIA-364-32, Test condition I) Mated Connector | | | | |
| | Sequence Group 4 | 1 cycles: -55 +0/-3 ℃, 30 minutes +85 +3/-0 ℃, 30 minutes (EIA-364-32, Test condition I) Mated Connector | | | | |
| | Sequence Group 4 See Product Qualification and Test | 1 cycles: -55 +0/-3 $^{\circ}$ C, 30 minutes +85 +3/-0 $^{\circ}$ C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40° C, $90\sim95\%$ RH, | | | | |
| Thermal Shock Humidity | Sequence Group 4 See Product Qualification and Test Sequence Group 4 | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to | | | | |
| Humidity | Sequence Group 4 See Product Qualification and Test | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to | | | | |
| Humidity | Sequence Group 4 See Product Qualification and Test Sequence Group 4 | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to | | | | |
| Humidity | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test | 1 cycles: -55 +0/-3 ℃, 30 minutes +85 +3/-0 ℃, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40℃, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105℃ for 96 | | | | |
| Humidity | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) | | | | |
| Humidity Temperature life | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test See Product Qualification and Test Sequence Group 5 | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) Subject mated/unmated | | | | |
| Humidity Temperature life | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test Sequence Group 5 See Product Qualification and Test See Product Qualification and Test | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) Subject mated/unmated connectors to 5% salt-solution | | | | |
| Humidity Temperature life | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test See Product Qualification and Test Sequence Group 5 | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) Subject mated/unmated connectors to 5% salt-solution concentration, 35°C,48 hours | | | | |
| | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test Sequence Group 5 See Product Qualification and Test Sequence Group 6 | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) Subject mated/unmated connectors to 5% salt-solution concentration, 35°C,48 hours (EIA-364-26) | | | | |
| Humidity Temperature life Salt Spray | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test Sequence Group 5 See Product Qualification and Test Sequence Group 6 Solder able area shall have | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) Subject mated/unmated connectors to 5% salt-solution concentration, 35°C,48 hours (EIA-364-26) And then into solder bath, | | | | |
| Humidity Temperature life | See Product Qualification and Test Sequence Group 4 See Product Qualification and Test Sequence Group 5 See Product Qualification and Test Sequence Group 6 | 1 cycles: -55 +0/-3 °C, 30 minutes +85 +3/-0 °C, 30 minutes (EIA-364-32, Test condition I) Mated Connector 40°C, 90~95% RH, 96 hours. (EIA-364-31,Condition A, Method II) Subject mated connectors to temperature life at 105°C for 96 hours. (EIA-364-17, Test condition A) Subject mated/unmated connectors to 5% salt-solution concentration, 35°C,48 hours (EIA-364-26) | | | | |

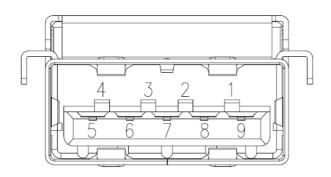
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PIN ASSIGNMENTS

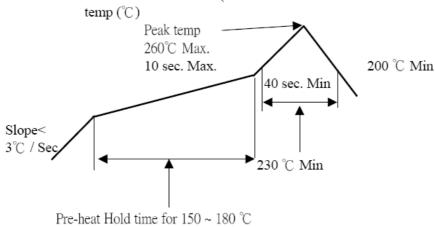


Schematic diagram

| Pin Number | Signal Name | | | | |
|------------|-------------|--|--|--|--|
| 1 | VBUS | | | | |
| 2 | D- | | | | |
| 3 | D+ | | | | |
| 4 | GND | | | | |
| 5 | StdA_SSRX- | | | | |
| 6 | StdA_SSRX+ | | | | |
| 7 | GND_DRAIN | | | | |
| 8 | StdA_SSTX- | | | | |
| 9 | StdA_SSTX+ | | | | |
| Shell | Shield | | | | |

INFRARED REFLOW CONDITION





is 60 ~ 120 sec.



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8 PRODUCT QUALIFICATION AND TEST SEQUENCE

| | Test Group | | | | | | | | | |
|---------------------------------|---------------|-------|-------|--------|-------|-------|---|---|---|----|
| Test or Examination | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 |
| | Test Sequence | | | | | | | | | |
| Examination of Product | | | | 1 . 7 | 1 . 6 | 1 \ 4 | | 1 | | |
| Low Level Contact Resistance | | 1 \ 5 | 1 \ 3 | 2 \ 10 | 2 \ 9 | 2 \ 5 | | 3 | | |
| Insulation Resistance | | | | 3 . 9 | 3、8 | | | | | |
| Dielectric Withstanding Voltage | | | | 4 \ 8 | 4 · 7 | | | | | |
| Temperature rise | 1 | | | | | | | | | |
| Insertion / Extraction Force | | 2 \ 4 | | | | | | | | |
| Durability | | 3 | | | | | | | | |
| Vibration | | | 2 | | | | | | | |
| Thermal Shock | | | | 5 | | | | | | |
| Humidity | | | | 6 | | | | | | |
| Temperature life | | | | | 5 | | | | | |
| Salt Spray | | | | | | 3 | | | | |
| Solder ability | | | | | | | 1 | | | |
| Resistance to Soldering Heat | | | | | | | | 2 | | |
| | | | | | | | | | | |
| Sample Size | 2 | 4 | 4 | 4 | 4 | 4 | 2 | 4 | | |

